

MNLH0071-0-H REV 0BLOriginal Creation Date: 09/18/95
Last Update Date: 12/20/96
Last Major Revision Date: 09/18/95**PRECISION BINARY BUFFERED REFERENCE****Industry Part Number**

LH0071

NS Part Numbers

LH0071-0H-MIL

Prime Die

LH0071

Processing

MIL-STD-883, Method 5004

Quality Conformance Inspection

MIL-STD-883, Method 5005

Subgrp Description Temp (°C)

1	Static tests at	+25
2	Static tests at	+125
3	Static tests at	-55
4	Dynamic tests at	+25
5	Dynamic tests at	+125
6	Dynamic tests at	-55
7	Functional tests at	+25
8A	Functional tests at	+125
8B	Functional tests at	-55
9	Switching tests at	+25
10	Switching tests at	+125
11	Switching tests at	-55

Electrical Characteristics

DC PARAMETERS

(The following conditions apply to all the following parameters, unless otherwise specified.)

DC: $V_i = 15V$, $R_L = 10K$

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
I_s	Quiescent Current (Functional)	$I_o = 0mA$			1	10	mA	1, 2, 3
V_o	Output Voltage (Functional)				9.75	10.75	V	1, 2, 3
V_o	Output Voltage	$V_o = 10.240V + \text{Output Accuracy}$	1		10.23	10.25	V	1
			1		10.209	10.271	V	2, 3
	Output Accuracy					± 0.1	%	1
						± 0.3	%	2, 3
	Line Regulation	$13V < V_i < 33V$				± 0.1	%	1
	Load Regulation	$0 < I_o < 5mA$				± 0.03	%	1, 2, 3
I_s	Quiescent Current	$V_i = 13V$			1	5	mA	1, 2, 3
		$V_i = 33V$			1	5	mA	1, 2, 3
	Change In Quiescent Current	$13V < V_i < 33V$				1.5	mA	1, 2, 3
	Output Voltage Change with Temp.	$25^\circ C < T_A < 85^\circ C$	3			± 0.2	%	1
		$-25^\circ C < T_A < 25^\circ C$	2			± 0.2	%	1
	Input Voltage Range		2		12.5	40	V	1, 2, 3
R_o	Output Resistance		1			1	Ohm	1, 2, 3
	Long Term Stability		2			± 0.2	%/YR	1

Note 1: Parameter tested go-no-go only.

Note 2: Guaranteed parameter not tested.

Note 3: This test is performed either on J273 when program is set to run with switch register = mode 1 (SEE FTS-LH0071H-R) or Drift oven tester per RPI-3-382.